Unit in mm

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL TYPE (PCT PROCESS)

2 S C 4 7 8 1

STOROBO FLASH APPLICATIONS

MEDIUM POWER AMPLIFIER APPLICATIONS

• High DC Current Gain and Excellent her Linearity

: $h_{FE(1)} = 200 \sim 600 \text{ (V}_{CE} = 2\text{V, I}_{C} = 1\text{A})$

: $h_{FE(2)} = 300$ (Typ.) ($V_{CE} = 2V$, $I_{C} = 4A$)

• Low Saturation Voltage

: $V_{CE (sat)} = 0.5V (Max.) (I_{C} = 4A, I_{B} = 80mA)$

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERIST	SYMBOL	RATING	UNIT				
Collector-Base Voltage		V _{CBO}	30	V			
Collector-Emitter Voltage		v_{CES}	30	V			
		v_{CEO}	10				
Emitter-Base Voltage		$V_{ m EBO}$	6	V			
Collector Current	DC	IC	4	A			
	Pulsed	ICP	8				
Base Current		I_{B}	0.8	A			
Collector Power Dissipation		PC	900	mW			
Junction Temperature		T_{j}	150	$^{\circ}\mathrm{C}$			
Storage Temperature Range		$\mathrm{T_{stg}}$	-55~150	$^{\circ}\mathrm{C}$			

0.75MAX. 1.0MAX. 0.8MAX. 0.6MAX. 1.27 1. EMITTER 2. COLLECTOR 3. BASE JEDEC EIAJ TOSHIBA 2-5J1A

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	I_{CBO}	$V_{CB} = 30V, I_{E} = 0$	_	_	100	nA
Emitter Cut-off Current	$I_{ m EBO}$	$V_{EB}=6V, I_C=0$	_	_	100	nA
Collector-Emitter Breakdown Voltage	V (BR) CEO	$I_{C}=10mA, I_{B}=0$	10	_	_	V
DC Current Gain	h _{FE (1)}	$V_{\text{CE}} = 2V, I_{\text{C}} = 1A$	200	_	600	
	$h_{\mathrm{FE}(2)}$	$V_{CE}=2V$, $I_{C}=4A$	140	300	—	
Collector-Emitter Saturation Voltage	V _{CE (sat)}	$I_{C} = 4A, I_{B} = 80mA$	_	0.28	0.5	V
Base-Emitter Voltage	$v_{ m BE}$	$V_{CE}=2V$, $I_{C}=4A$	_	1.0	1.5	V
Transition Frequency	${ m f_T}$	$V_{CE} = 2V, I_{C} = 0.5A$	_	170	_	MHz
Collector Output Capacitance	C_{ob}	$V_{CB} = 10V, I_E = 0, f = 1MHz$	_	50	_	pF

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